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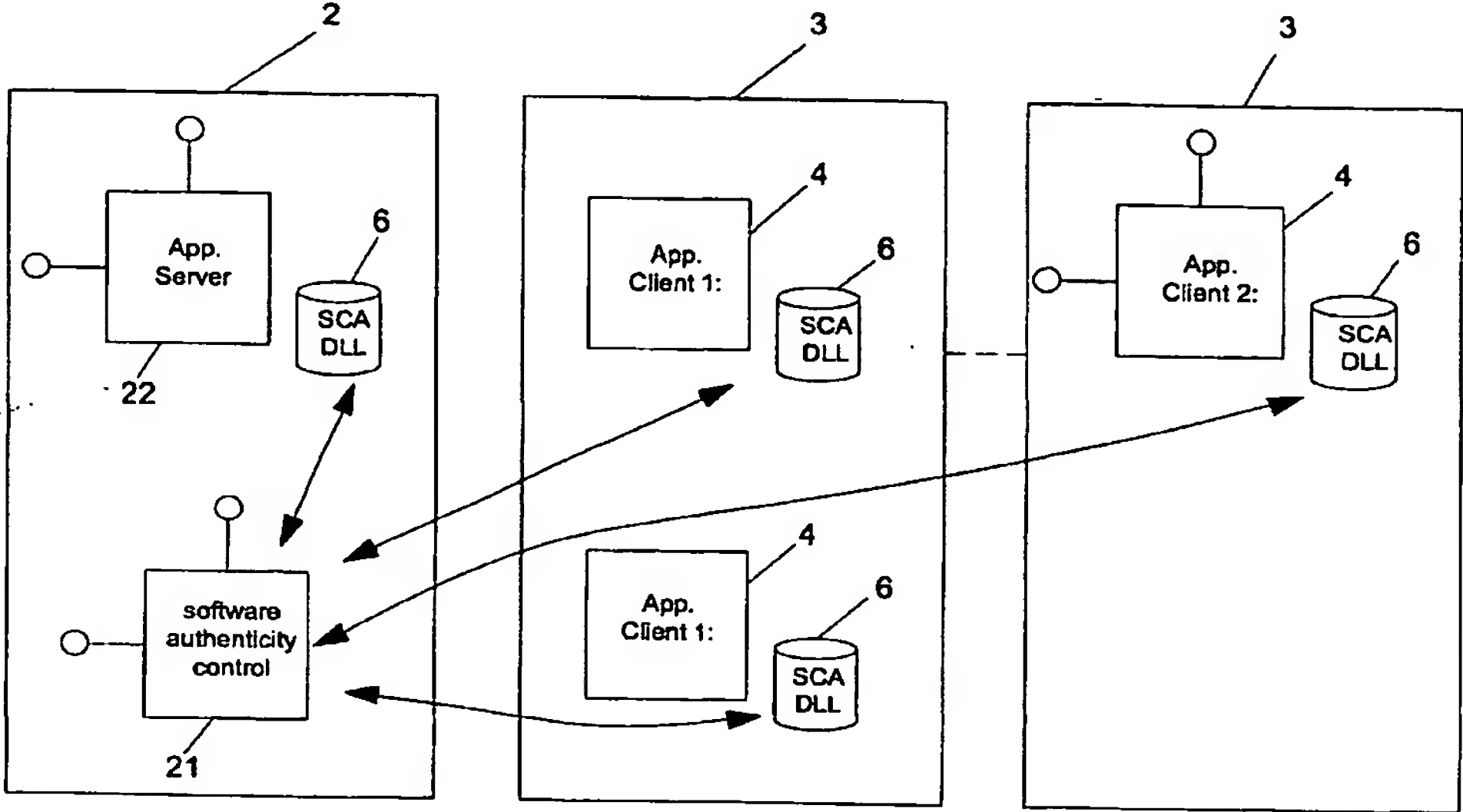
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(54) Title: METHOD AND SYSTEM FOR CONTROLLING AN ELECTRONIC INSTRUMENT FOR METROLOGICAL MEASUREMENTS



(57) Abstract: Control system of an electronic instrument for metrological measurements, comprising an electronic local processing unit including a handling application of said instrument. The system includes a control application for said handling application, which can be associated with said local processing unit, said control application being suitable for generating a univocal certification code for the application.

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